

**MRS** Advances

# Electronic and Photonic Materials

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# MRS Advances: Electronic and Photonic Materials

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# CONTENTS

<b>Catastrophic Optical Bulk Damage – A New Failure Mode in High-power InGaAs-AlGaAs Strained Quantum Well Lasers. . . . .</b>	<b>3329</b>
Yongkun Sin, Zachary Lingley, Talin Ayvazian, Miles Brodie, and Neil Ives	
<b>Dynamics, Design, and Application of a Silicon-on-insulator Technology Based Neuron . . . . .</b>	<b>3347</b>
S. Dutta, T. Chavan, S. Shukla, V. Kumar, A. Shukla, N. Mohapatra, and U. Ganguly	
<b>Defect Characterization of UMG mc-Si Solar Cells Using LBIC and Luminescence Imaging Techniques. . . . .</b>	<b>3359</b>
L.A. Sánchez, A. Moretón, M. Guada, S. Rodríguez-Conde, O. Martínez, and J. Jiménez	
<b>Metal Whisker Growth Induced by Localized, High-intensity DC Electric Fields . . . . .</b>	<b>3367</b>
Vamsi Borra, Osama Oudat, Daniel G. Georgiev, Victor G. Karpov, and Diana Shvydka	
<b>Characterization of Plasma Induced Damage and Strain on InP Patterns and their Impact on Luminescence . . . . .</b>	<b>3373</b>
Marc Fouchier, Maria Fahed, Erwine Pargon, Névine Rochat, Jean-Pierre Landesman, Denis Rouchon, Joyce Roque, Karine Rovayaz, Eugénie Martinez, and Sébastien Labau	
<b>Comparative Study of Surface Energies of Native Oxides of Si(100) and Si(111) via Three Liquid Contact Angle Analysis . . . . .</b>	<b>3379</b>
Saaketh R. Narayan, Jack M. Day, Harshini L. Thinakaran, Nicole Herbots, Michelle E. Bertram, Christian E. Cornejo, Timoteo C. Diaz, Karen L. Kavanagh, R.J. Culbertson, Franscesca J. Ark, Sukesh Ram, Mark W. Mangus, and Rafiqul Islam	
<b>Optoelectronics Properties of Tungsten Oxide Nanoparticle Networks Deposited by Flame Spray Pyrolysis . . . . .</b>	<b>3391</b>
Domenico Caputo, Shaul Ajò, Giampiero de Cesare, Alessio Buzzin, Renheng Bo, and Antonio Tricoli	

<b>Material Reliability of Low-temperature Boron Deposition for PureB Silicon Photodiode Fabrication. . . . .</b>	<b>3397</b>
L.K. Nanver, K. Lyon, X. Liu, J. Italiano, and J. Huffman	
<b>Measuring Surface Energies of GaAs (100) and Si (100) by Three Liquid Contact Angle Analysis (3LCAA) for Heterogeneous Nano-Bonding™ . . . . .</b>	<b>3403</b>
Christian E. Cornejo, Michelle E. Bertram, Timoteo C. Diaz, Saaketh R. Narayan, Sukesh Ram, Karen L. Kavanagh, Nicole Herbots, Jack M. Day, Franscesca J. Ark, Ajit Dhamdhare, Robert J. Culbertson, and Rafiqul Islam	
<b>Reconfiguration of van der Waals Gaps as the Key to Switching in GeTe/Sb<sub>2</sub>Te<sub>3</sub> Superlattices . . . . .</b>	<b>3413</b>
A.V. Kolobov, P. Fons, Y. Saito, and J. Tominaga	
<b>Electric Field Effects in Chalcogenides . . . . .</b>	<b>3419</b>
Litian Chew, Weiling Dong, Alok Ranjan, Jitendra K. Behera, Li Lu, and Robert E. Simpson	